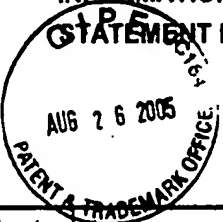


INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		Application Number		10/649,474			
		Filing Date		August 26, 2003			
		First Named Inventor		Gregory R. Hanson et al.			
		Group Art Unit		2877			
		Examiner Name		Connolly, Patrick J			
Sheet	1	of	2	Attorney Docket Number		UBAT1520	
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Examiner Signature		PATRICK CONNOLLY				Date Considered	09.21.2005

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Examiner Signature		PATRICK CONNOLLY		Date Considered	09.21.2005